**Product data sheet** 

## 1. General description

Planar passivated high commutation three quadrant triac in a SOT223 surface mountable plastic package. This "series ET" triac balances the requirements of commutation performance and gate sensitivity and is intended for interfacing with low power drivers and logic ICs including microcontrollers.

### 2. Features and benefits

- 3Q technology for improved noise immunity
- Direct gate triggering from low power drivers and logic ICs
- High commutation capability with very sensitive gate
- High voltage capability
- Planar passivated for voltage ruggedness and reliability
- Surface mountable package
- · Triggering in three quadrants only
- · Very sensitive gate for easy logic level triggering

# 3. Applications

- · Low power motor controls
- · Small inductive loads e.g. solenoids, door locks, water valves
- Small loads in large white goods

### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes		Values		Unit
Absolute	maximum rating						
$V_{DRM}$	repetitive peak off-state voltage				800		V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; $T_{sp} \le 127 ^{\circ}\text{C}$ ; Fig. 1; Fig. 2; Fig. 3		1			А
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 20 \text{ ms}$ ; Fig. 4; Fig. 5		11			А
		full sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> = 16.7 ms			12.1		Α
T <sub>j</sub>	operating junction temperature			-40 to 150		0	°C
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G+;$ $T_j = 25 \text{ °C; } Fig. 9$		0.5	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 9$		0.5	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_i = 25 \text{ °C; } Fig. 9$		0.5	-	10	mA

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>		-	-	12	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 0.85 A; T <sub>j</sub> = 25 °C; <u>Fig. 12</u>		-	1.35	1.60	V
Dynamic	characteristics				,	,	
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_{j}$ = 150 °C; $R_{GT1}$ = 100 Ω; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform		600	-	-	V/µs
dl <sub>com</sub> /dt	rate of change of commutating current	$V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 0.8 \text{ A};$ $dV_{com}/dt = 10 \text{ V/}\mu\text{s}; gate open circuit}$		1.6	-	-	A/ms

# 5. Pinning information

## **Table 2. Pinning information**

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1		2
2	T2	main terminal 2		T2 T1
3	G	gate		sym051
4	T2	main terminal 2	1 2 3	

# 6. Ordering information

### Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
BTA301W-800ET	SOT223	BTA301W-800ETF	Reel	4000	SOT223	16-Mar-2006

# 7. Marking

### **Table 4. Marking codes**

Type number	Marking codes			
	Assembly factory: d	Assembly factory: L		
BTA301W-800ET	Jdxxx 301W8E	JLxxx 301W8E		

# 8. Limiting values

#### Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage			800	V
$V_{RRM}$	repetitive peak reverse voltage			800	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; $T_{sp} \le 127 ^{\circ}\text{C}$ ; Fig 1; Fig 2; Fig 3		1	Α
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 20 \text{ ms}$ ; Fig 4; Fig 5		11	Α
		full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 16.7 ms		12.1	Α
l <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10 ms; SIN		0.61	A <sup>2</sup> s
dl <sub>⊤</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 20 mA		100	A/µs
I <sub>GM</sub>	peak gate current			1	Α
$P_GM$	peak gate power			2	W
$P_{G(AV)}$	average gate power	over any 20 ms period		0.1	W
T <sub>stg</sub>	storage temperature			-40 to 150	°C
T <sub>j</sub>	operating junction temperature			-40 to 150	°C

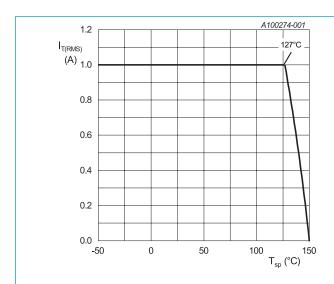
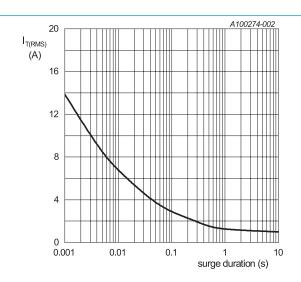
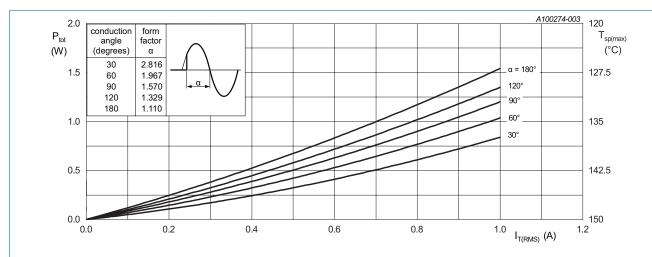


Fig. 1. RMS on-state current as a function of solder point temperature; maximum values



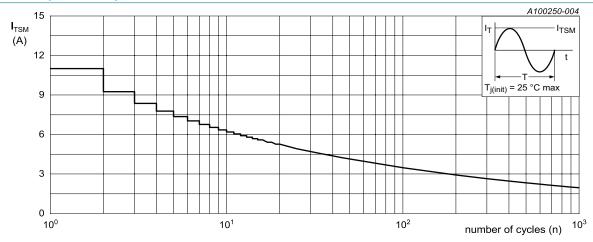
f = 50 Hz;  $T_{sp}$  = 127 °C Fig. 2. RMS on-state current as a function of surge duration; maximum values



 $\alpha$  = conduction angle

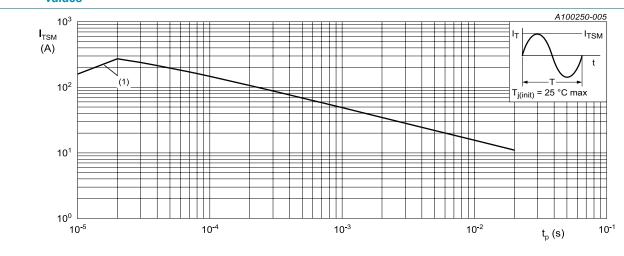
 $a = form factor = I_{T(RMS)} / I_{T(AV)}$ 

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum



 $t_p \le 20 \text{ ms}$ (1)  $dI_T/dt \text{ limit}$ 

Fig. 5. Non-repetitive peak on-state current as a function of pulse width; maximum values

# 9. Thermal characteristics

**Table 6. Thermal characteristics** 

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
$R_{\text{th(j-sp)}}$	thermal resistance from junction to solder point	full cycle; Fig 6		-	-	15	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient in free air; printed-circuit board mounted; minimum footprint; Fig 7			-	156	-	K/W
		in free air; printed-circuit board mounted; pad area; Fig 8		-	70	-	K/W

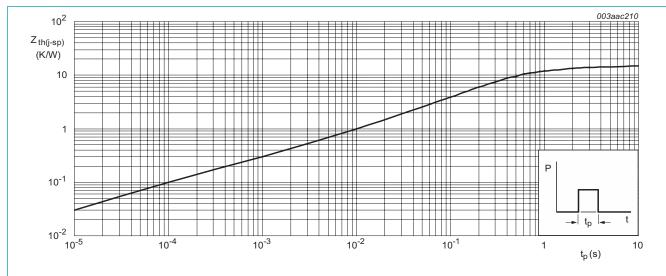
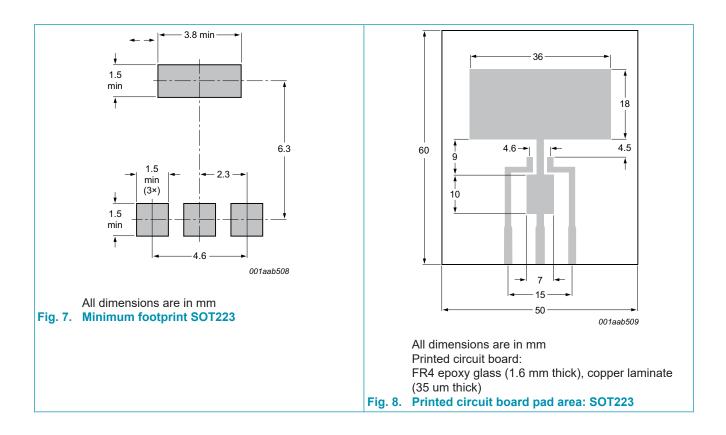


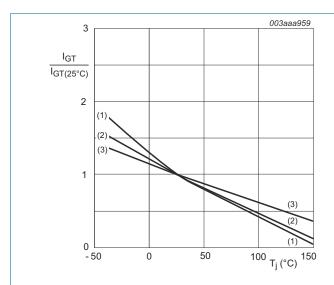
Fig. 6. Transient thermal impedance from junction to solder point as a function of pulse width



# 10. Characteristics

### Table 7. Characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
I <sub>GT</sub> g	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 9$		0.5	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 9$		0.5	-	10	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 9$		0.5	-	10	mA
IL	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2+ G+};$ $T_j = 25 \text{ °C}; \underline{\text{Fig. 10}}$		-	-	12	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2+ G-};$ $T_j = 25 \text{ °C}; \underline{\text{Fig. 10}}$		-	-	20	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 \text{ °C}; \text{ Fig. 10}$		-	-	12	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>		-	-	12	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 0.85 A; T <sub>j</sub> = 25 °C; <u>Fig. 12</u>		-	1.35	1.60	V
$V_{GT}$	gate trigger voltage	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T_j = 25 \text{ °C;}$ Fig. 13		-	0.9	1.5	V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 \text{ °C}$		0.2	0.3	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C		-	0.1	2	mA
I <sub>R</sub>	reverse current	V <sub>R</sub> = 800 V; T <sub>j</sub> = 150 °C		-	0.1	2	mA
Dynamic	characteristics						
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 150 °C; $R_{GT1}$ = 100 Ω; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform		600	-	-	V/µs
dI <sub>com</sub> /dt	rate of change of commutating current	$V_D = 400 \text{ V; } T_j = 125 \text{ °C; } I_{T(RMS)} = 0.8 \text{ A; } dV_{com}/dt = 10 \text{ V/}\mu\text{s; gate open circuit}$		1.6	-	-	A/ms





- (2) T2+ G-
- (3) T2+ G+

Fig. 9. Normalized gate trigger current as a function of junction temperature

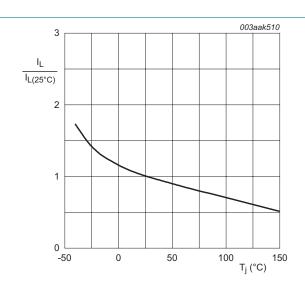


Fig. 10. Normalized latching current as a function of junction temperature

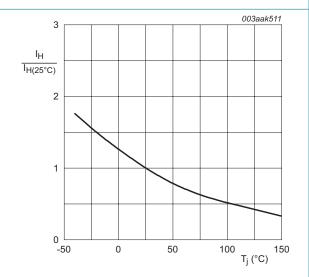
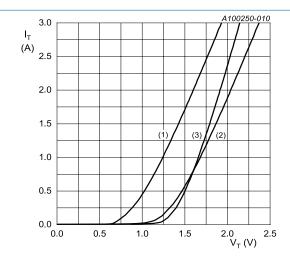


Fig. 11. Normalized holding current as a function of junction temperature



 $V_o$  = 1.286 V;  $R_s$  = 0.3824  $\Omega$  (1)  $T_j$  = 150 °C; typical values

(2) T<sub>i</sub> = 150 °C; maximum values

(3) T<sub>i</sub> = 25 °C; maximum values

Fig. 12. On-state current as a function of on-state voltage

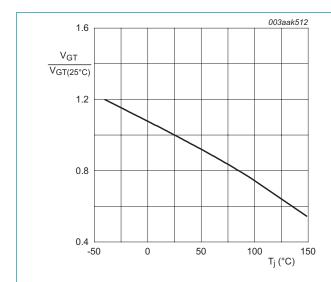
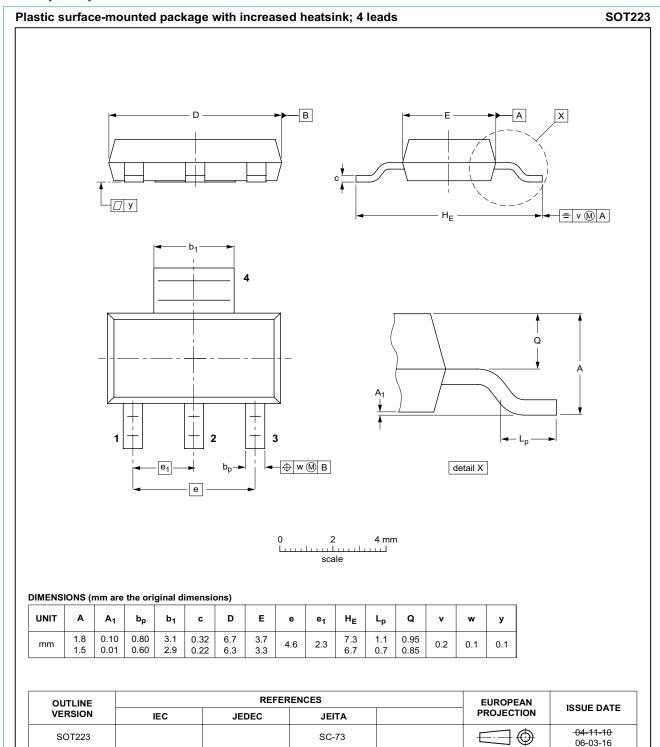


Fig. 13. Normalized gate trigger voltage as a function of junction temperature

# 11. Package outline

Assembly factory: d & L



# 12. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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**BTA301W-800ET** 

**3Q Hi-Com Triac** 

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